

Application/Control No.	Applicant(s)/Patent under Reexamination
10/766,660	CARNAHAN ET AL.
Examiner	Art Unit

David E. Martinez

2181

	SEARCHED				
Class	Subclass	Date	Examiner		
710	62,63,72	5/11/2006	DM		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East see attached	5/11/2006	DM		
Inventor Search eDan	5/11/2006	DM		
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwent, IBM_TDB.	5/11/2006	DM		